

Hardware Documentation

Preliminary Data Sheet

HAL[®] 3715, HAL 372x, HAL 373x

Robust Programmable
2D Position Sensor Family
with Arbitrary Output Function



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Robust Programmable 2D Position Sensor Family with Arbitrary Output Function

Release Note: Revision bars indicate significant changes to the previous document.

1. Introduction

The HAL 37xy is the second generation of sensors using Micronas' proprietary 3D HAL technology. This new family has several members. HAL 372x provides a linear, ratiometric analog output signal with integrated wire-break detection working with pull-up or pull-down resistors. Compared to HAL 372x, the HAL 3715 is splitting the 360° measurement range either into four repetitive 90° (MOD 90°) or three 120° (MOD 120°) segments. HAL 373x features digital output formats like PWM and SENT (according to SAE-J2716 release 2010). The digital output format is customer programmable. The PWM output is configurable with frequencies between 0.2 kHz and 2 kHz with up to 12 bit resolution.

Conventional planar Hall technology is only sensitive to the magnetic field orthogonal to the chip surface. In addition to the orthogonal magnetic field, HAL 37xy is also sensitive for magnetic fields applied in parallel to the chip surface. This is possible by integrating vertical Hall plates into the standard CMOS process.

The sensor cell can measure three magnetic field components BX, BY, and BZ. This enables a new set of applications for position detection, like wide distance, angle or through-shaft angular measurements. The table below describes the different family members.

Туре	Output Format	Detectable Field Component
HAL 3715	Analog/Modulo	B_X and B_Y
HAL 3725	Analog	B_X and B_Y
HAL 3726	Analog	B_Y and B_Z
HAL 3727	Analog	B_X and B_Z
HAL 3735	PWM & SENT	B _X and B _Y
HAL 3736	PWM & SENT	B _Y and B _Z
HAL 3737	PWM & SENT	B _X and B _Z

On-chip signal processing calculates the angle from two of the magnetic field components and converts this value to an output signal. Due to the measurement method, the sensor exhibits excellent drift performance over the specified temperature range resulting in a new class of accuracy for angular or linear measurements. Additionally to the built-in signal processing, the sensor features an arbitrary programmable linear characteristic for linearization of the output signal (with up to 33 setpoints).

Major characteristics like gain and temperature dependent offset of X/Y- and Z-channel, reference position, phase shift between X/Y- and Z-signal, hysteresis, low-pass filter frequency, output slope, and offset and clamping levels can be adjusted to the magnetic circuitry by programming the non-volatile memory.

The sensors contain advanced on-board diagnostic features that enhance fail-safe detection. In addition to standard checks, such as overvoltage and undervoltage detection and wire break, internal blocks such as ROM and signal path are monitored during normal operation. For devices with a selected PWM output, the error modes are indicated by a change of PWM frequency and duty-cycle. For SENT output a dedicated error code will be transmitted.

The devices are designed for automotive and industrial applications and operate in a junction temperature range from –40 °C up to 170 °C.

The sensors are available in a four-pin leaded transistor package TO92UP, as well as in a SOIC8 package.

1.1. Major Applications

Due to the sensor's versatile programming characteristics and its high accuracy, the HAL 37xy is the optimal system solution for applications such as:

- Linear movement measurement,
 - · EGR valve position
 - Clutch pedal position
 - Cylinder and valve position sensing
- Rotary position measurement, like
 - · Gear selector
 - Throttle valve position, etc.
 - Chassis position sensors (ride-height control) with HAL 3715
- Joystick
- Non-contact potentiometer

1.2. Features

- Angular and position measurement extremely robust against temperature and stress influence
- 12 bit ratiometric linear analog output for HAL 372x
- Modulo 90°/120° for HAL 3715
- 0.2 kHz to 2 kHz PWM (up to 12 bit) or 12 bit SENT output for HAL 373x
- Programmable arbitrary output characteristic with up to 33 setpoints
- 8 kHz sampling frequency
- Operates from 4.5 V up to 5.5 V supply voltage
- Operates from –40 °C up to 170 °C junction temperature
- Programming via the sensor's output pin
- Programmable characteristics in a non-volatile memory (EEPROM) with redundancy and lock function
- Programmable first-order low-pass filter
- Programmable hysteresis on X/Y or Z-channel
- Programmable output gain and offset
 - X/Y- and Z-channel gain of signal path programmable
 - Second-order temperature-dependent offset of signal path programmable for X/Y- or Z-channel
 - Phase shift between X/Y- and Z-channel programmable
 - Programmable offset before angle calculation block
 - Programmable output clamping for error band definition
 - Programmable reference position
 - Programmable magnetic detection range
 - 32 bit identification number for customer
 - 32 bit identification number with Micronas production information (like X,Y position on production wafer)
 - On-board diagnostics of different functional blocks of the sensor
 - Short-circuit protected push-pull output
 - Over- and reverse voltage protection at V_{SUP}
 - Under- and overvoltage detection of V_{SUP}
 - Wire-break detection with pull-up or pull-down resistor
 - EMC and ESD robust design

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2. Ordering Information

A Micronas device is available in a variety of delivery forms. They are distinguished by a specific ordering code:

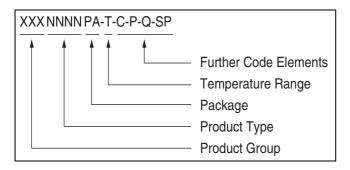


Fig. 2-1: Ordering Code Principle

For a detailed information, please refer to the brochure: "Hall Sensors: Ordering Codes, Packaging, Handling".

2.1. Device-Specific Ordering Codes

The HAL 37xy is available in the following package and temperature variants.

Table 2-1: Available packages

Package Code (PA)	Package Type
DJ	SOIC8-1
UP	TO92UP-1

Table 2–2: Available temperature ranges

Temperature Code (T)	Temperature Range	
Α	$T_{J} = -40 ^{\circ}\text{C} \text{ to } +170 ^{\circ}\text{C}$	

The relationship between ambient temperature (T_A) and junction temperature (T_J) is explained in Section 5.1. on page 30.

For available variants for Configuration (C), Packaging (P), Quantity (Q), and Special Procedure (SP) please contact Micronas.

Table 2–3: Available ordering codes and corresponding package marking

Available Ordering Codes	Package Marking
HAL3715DJ-A-[C-P-Q-SP]	3715A
HAL3715UP-A-[C-P-Q-SP]	3715A
HAL3725DJ-A-[C-P-Q-SP]	3725A
HAL3725UP -A-[C-P-Q-SP]	3725A
HAL3726DJ-A-[C-P-Q-SP]	3726A
HAL3726UP-A-[C-P-Q-SP]	3726A
HAL3727DJ-A-[C-P-Q-SP]	3727A
HAL3727UP-A-[C-P-Q-SP]	3727A
HAL3735DJ-A-[C-P-Q-SP]	3735A
HAL3735UP -A-[C-P-Q-SP]	3735A
HAL3736DJ-A-[C-P-Q-SP]	3736A
HAL3736UP-A-[C-P-Q-SP]	3736A
HAL3737DJ-A-[C-P-Q-SP]	3737A
HAL3737UP-A-[C-P-Q-SP]	3737A

3. Functional Description

3.1. General Function

HAL 3715, HAL 372x and HAL 373x are 2D position sensors based on Micronas' 3D HAL technology. The sensors include two vertical and one horizontal Hall plate with spinning current offset compensation for the detection of X, Y or Z magnetic field components, a signal processor for calculation and signal conditioning of two magnetic field components, protection devices, and a ratiometric linear analog, PWM or SENT output.

The spinning current offset compensation minimizes the errors due to supply voltage and temperature variations as well as external package stress. The signal path of HAL37xy consist of two channels (CH1 and CH2). Depending on the product variant two out of the three magnetic field components are connected to Channel 1 and Channel 2.

The sensors can be used for angle measurements in a range between 0° and 360° (end of shaft and through shaft setup) as well as for robust position detection (linear movement or position). The in-system calibration can be utilized by the system designer to optimize performance for a specific system. The calibration information is stored in an on-chip EEPROM.

The HAL37xy is programmable by modulation of the output voltage. No additional programming pin is needed.

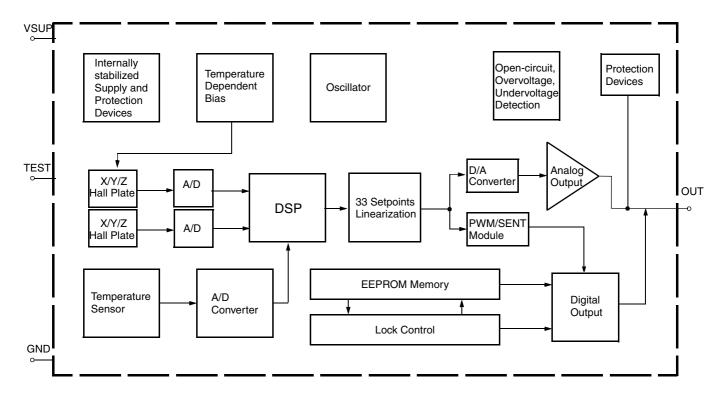


Fig. 3-1: HAL37xy block diagram

3.2. Signal Path and Register Definition

3.2.1. Signal Path

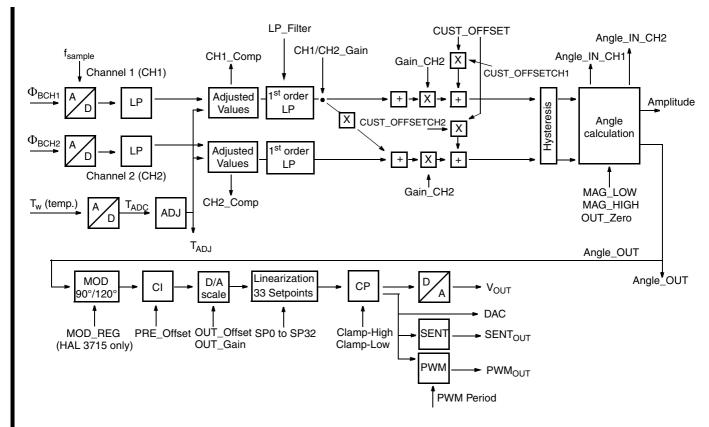


Fig. 3-2: Signal path of HAL37xy

3.2.2. Register Definition

The DSP part of this sensor performs the signal conditioning. The parameters for the DSP are stored in the EEPROM/NVRAM register. Details of the signal path are shown in Fig. 3.2.

Terminology:

GAIN: name of the register or register value

Gain: name of the parameter

The sensor signal path contains two kinds of registers. Registers that are readout only (RAM) and programmable registers EEPROM/NVRAM. The RAM registers contain measurement data at certain steps of the signal path and the EEPROM/NVRAM registers have influence on the sensors signal processing.

3.2.2.1. RAM Registers

TADJ

The TADJ register contains the digital value of the sensor junction temperature. It has a length of 16 bit and is binary coded. From the 16 bit only the range between 0 ... 32767 is used for the temperature information. Typically the temperature sensor is calibrated in the way that at $-40~^{\circ}\text{C}$ the register value is 100 LSB and at 160 $^{\circ}\text{C}$ it is 12000 LSB.

CH1_COMP and CH2_COMP

CH1_COMP and CH2_COMP register contain the temperature compensated magnetic field information of channel 1 and channel 2. Both registers have a length of 16 bit each and are two's-complement coded. Therefore, the register values can vary between -32768 ... 32767.

ANGLE_IN_CH1 and ANGLE_IN_CH2

ANGLE_IN_CH1 and ANGLE_IN_CH2 register contain the customer compensated magnetic field information of channel 1 and channel 2 used for the angle calculation. These registers include already customer phase-shift, gain and offset correction as well as an hysteresis. Both registers have a length of 16 bit each and are two's-complement coded. Therefore, the register values can vary between -32768 ... 32767.

ANGLE_OUT

The ANGLE_OUT register contains the digital value of the position calculated by the angle calculation algorithm. It has a length of 16 bit and is binary. From the 16 bit only the range between 0 ... 32767 is used for the position information. Position can either be an angular position (angle) or a virtual angle calculated out of two magnetic field directions in case of linear position measurements.

DAC

The DAC register contains the digital equivalent of the output voltage, PWM output duty-cycle or the SENT data. It has a length of 16 bit and is binary. From the 16 bit only the range between 0 ... 32767 is used for the position information. Position can either be an angular position (angle) or a virtual angle calculated out of two magnetic field directions in case of linear position measurements.

ANGLE_AMP

The ANGLE_AMP register contains the digital value of the magnetic field amplitude calculated by the angle calculation algorithm. From mathematical point of view the amplitude can be calculated from the signals in channel 1 and channel 2 (X-/Y-/Z-components).

Example:

Amplitude =
$$\sqrt{CH1^2 + CH2^2}$$

The angle calculation algorithm adds a factor of roughly 1.6 to the equation for the magnetic amplitude. So the equation for the amplitude is defined as follows:

ANGLE_AMP
$$\cong 1.6 \times \sqrt{CH1^2 + CH2^2}$$

DIAGNOSIS

The DIAGNOSIS register identifies certain failures detected by the sensor. HAL37xy performs self-tests during power-up of the sensor and also during normal operation. The result of these self tests is stored in the DIAGNOSIS register. DIAGNOSIS register is a 16 bit register.

Bit no.	Function	Description
15:10	None	Reserved
9	DAC Output High Clamping	This bit is set to 1 in case that the high clamping value of the DAC is reached.
8	DAC Output Low Clamping	This bit is set to 1 in case that the low clamping value of the DAC is reached.
7	Channel 1 Clipping	These bits are set to 1 in case that the A/D converter in channel 1 and/or 2 detects an under- or
6	Channel 2 Clipping	overflow
5	DSP Self Test	The DSP is doing the internal signal processing like angle calculation, temperature compensation, etc.
		This bit is set to 1 in case that the DSP self test fails. (continuously running)
4	EEPROM Self Test	This bit is set to 1 in case that the EEPROM self test fails. (Performed during power-up only)
3	ROM Check	This bit is set to 1 in case that ROM parity check fails. (continuously running)
2	None	Reserved
1	MAGHI	This bit is set to 1 in case that the magnetic field is exceeding the MAG-HI register value (magnetic field to high)
0	MAGLO	This bit is set to 1 in case that the magnetic field is below the MAG-LOW register value (magnetic field to low)

Details on the sensor self tests can be found in Section 3.5. on page 15.

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PROG_DIAGNOSIS

The PROG_DIAGNOSIS register allows the customer to identify errors occurring during programming and writing of the EEPROM or NVRAM. The customer must check the first and second acknowledge. To enable debugging of the production line it is recommended to read back the PROG_DIAGNOSIS register in case of a missing second acknowledge. Please check the Programming Guide for HAL37xy for further details.

The PROG_DIAGNOSIS register is a 16 bit register. The following table shows the different bits indicating certain error possibilities.

Bit no.	Function	Description
15:11	None	Reserved
10	Charge Pump Error	This bit is set to 1 in case that the internal programming voltage was too low
9	Voltage Error during Program/ Erase	This bit is set to 1 in case that the internal supply voltage was too low during program or erase
8	NVRAM Error	This bit is set to 1 in case that the programming of the NVRAM failed
5:0	Programming	These bits are used for programming the memory

3.2.2.2. EEPROM Registers

CH1/CH2_GAIN

CH1/CH2_GAIN can be used to compensate a phase-shift between channel 1 and channel 2. The register has a length of 16 bit. It is possible to make a phase shift correction of ±75°. The step size and therefore the smallest possible correction is 0.002°. The register is two's-complement coded and ranges from -32768 to 32767. The register value is sin function based.

Neutral value for this register is zero (no Phase-shift correction).

Note: In case the phase-shift correction is used, then it is necessary to adapt the settings of GAIN_CH2 too. For details see definition of GAIN_CH2.

GAIN_CH1 and GAIN_CH2

GAIN_CH1 and GAIN_CH2 can be used to compensate amplitude mismatches between channel 1 and channel 2. Micronas delivers pre calibrated sensors with compensated gain mismatch between channel 1 and channel 2. Nevertheless it is possible that due to the magnetic circuit a mismatch between channel 1 and channel 2 gain occurs. This can be compensated with GAIN_CH1 and GAIN_CH2.

Both registers have a length of 16 bit and are two's-complement coded. Therefore, they can have values between -32768 and 32767 (-2 ... 2). For neutral settings both register values have to be set to 1 (register value 16384).

In case that the phase-shift correction is used it is necessary to change also the gain of channel 2 (see also CH1/CH2_GAIN). If phase-shift correction is used the corresponding register has to be set to

$$GAIN_CH2 = \frac{16384}{\cos(Phase-shift)}$$

Note: In case GAIN_CH1 or GAIN_CH2 exceed the range of -2 ... 2 (-32768 ... 32767), then it is possible to reduce the gain of the opposite channel for compensation.

CUST_OFFSET

CUST_OFFSET can be used to compensate an offset in channel 1 and channel 2. Micronas delivers pre calibrated sensors. Nevertheless it is possible that due to the magnetic circuit an offset in channel 1 and channel 2 occurs. This can be compensated with CUST OFFSET.

The customer offset can also have a temperature coefficient to follow the temperature coefficient of a magnet. The customer offset consists of a polynomial of second-order represented by the three registers CUST_OFFSET1...3.

The customer offset can be added to channel 1 and/or channel 2 by the selection coefficients CUST_OFFSETCH1 and CUST_OFFSETCH2. Additionally these two registers can be used to scale the temperature dependent offset between 0% and 100%

All five registers have a length of 16 bit each and are two's-complement coded. Therefore, they can have values between –32768 and 32767.

HYSTERESIS

HYSTERESIS defines the number of digital codes used as an hysteresis on channel 1 and channel 2 before the angle calculation. The purpose of this register is to avoid angle variation on the ANGLE_OUT register and finally on the output signal due to the noise on the ANGLE IN CH1 and ANGLE IN CH2 signals.

The register has a length of 16 bit and is two's complement number.

It is possible to program a hysteresis between 1 LSB and 16383 LSB. The register value itself must be stored as a negative value.

The hysteresis function is deactivated by setting the register value to zero.

OUT_ZERO

OUT_Zero defines the reference position for the angle output. It can be set to any value of the output range. It is the starting point/reference for the 33 setpoints. OUT_ZERO has a register length of 16 bit and it is two's-complement coded.

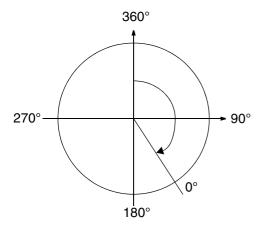


Fig. 3-3: Example definition of zero degree point

Secondly this angle can be used to shift the PI discontinuity point of the angle calculation to the maximum distance from the required angular range in order to avoid the 360°-wrapping of the output due to noise.

PRE_OFFSET

The PRE_OFFSET register allows to shift the angular range to avoid an overflow of the internal 16 bit calculation/signal path.

The PRE_OFFSET register has a length of 16 bit and is two's-complement coded.

OUT_GAIN

OUT_GAIN defines the gain of the output signal. The register has a length of 16 bit and is two's-complement coded. OUT_GAIN = 1 is neutral setting and leads to a change of the output signal from 0% to 100% for an angle change from 0° to 360° (if OUT_OFFSET is set to 0).

OUT_GAIN can be changed between -64 and 64.

OUT_OFFSET

OUT_OFFSET defines the offset of the output signal. The register has a length of 16 bit and is two's complement coded. OUT_OFFSET = 0 is neutral setting and leads to a change of the output signal from 0% to 200% of full scale for an angle change from 0° to 360° (If OUT_GAIN is set to 1).

OUT_Offset can be changed between -200% and 200% of full scale. OUT_OFFSET = 0 leads to a voltage offset of 0% of full scale and OUT_OFFSET = 32768 leads to a offset of -200% of full scale.

Clamping Levels (CLAMP-LOW & CLAMP-HIGH)

The clamping levels CLAMP_LOW and CLAMP_HIGH define the maximum and minimum output voltage of the analog output. The clamping levels can be used to define the diagnosis band for the sensor output. Both registers have a bit length of 16 bit and are two's-complemented coded. Both clamping levels can have values between 0% and 100% of full scale.

Magnetic Range Check

The magnetic range check uses the magnitude output and compares it with an upper and lower limit threshold defined by the registers MAG-LOW and MAG-HIGH. If either low or high limit is exceeded then the sensor will indicate it with an overflow on the sensors output (output high clamping).

MAG-LOW

MAG-LOW defines the low level for the magnetic field range check function. This register has a length of 16 bit and is two's complement number.

MAG-HIGH

MAG-HIGH defines the high level for the magnetic field range check function. This register has a length of 16 bit and is two's complement number.

Low-Pass Filter

With the LP_Filter register it is possible to select different –3dB frequencies for HAL37xy. The low-pass filter is a 1st-order digital filter and the register is 16 bit organized. Various typical filter frequencies between 4 kHz (no filter) and 10 Hz are available.

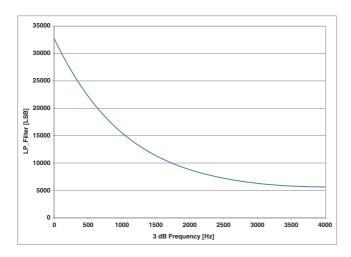


Fig. 3-4: 3dB filter frequency vs. LP_FILTER codes

Modulo Select

The MODULO_Select register is only available in HAL 3715. With this register, the customer can switch between Modulo 90° and 120° output.

HAL 3715 is splitting the 360° measurement range either into four repetitive 90° (MOD 90°) or three 120° (MOD 120°) segments.

3.3. Output Linearization

In certain applications (e.g. through shaft applications or position measurements) it is required to linearize the output characteristic. The resulting output characteristic "value vs. angle/position" is not a linear curve as in the ideal case. But it can be linearized by applying an inverse nonlinear compensation curve.

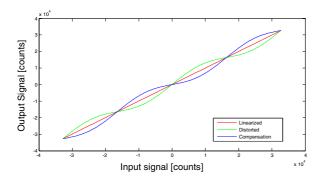


Fig. 3–5: Example for output linearization

For this purpose the compensation curve will be divided into 33 segments with equal distance. Each segment is defined by two setpoints, which are stored in EEPROM. Within the interval, the output is calculated by linear interpolation according to the position within the interval.

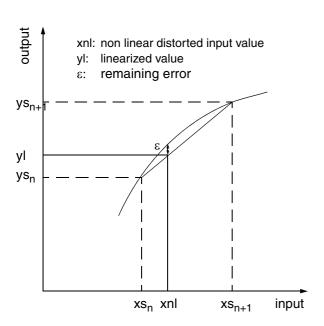


Fig. 3-6: Linearization - detail

The constraint of the linearization is that the input characteristic has to be a monotonic function. In addition, it is recommended that the input does not have a saddle point or inflection point, i.e. regions where the input is nearly constant. This would require a high density of set points.

To do a linearization the following steps are necessary:

- Measure output characteristics over full range
- Find the inverse (Point-wise mirroring the graph on the bisectrix)
- Do a spline fit on the inverse
- Insert digital value of set point position into spline fit function for each set point (0, 1024, 2048, ..., 32768)
- Resulting values can be directly entered into the EEPROM

3.4. NVRAM Register

Customer Setup

The CUST_SETUP register is a 16 bit register that enables the customer to activate various functions of the sensor like diagnosis modes, functionality mode, customer lock, communication protocol speed, etc.

Table 3-1: Customer Setup Register

Bit no.	Function	Description
15	None	Reserved
14	EEPROM Self-Test	EEPROM Self-Test Mode (latched) 0: Running during Power-Up 1: Continuously
13	Communication speed	Communication protocol bit time speed 0: typ. 1 ms 1: typ. 0.25 ms
12	DIGMOD	Output format for HAL 373x devices 0: PWM output 1: SENT output
11:10	PWMFREQ	Defines the frequency of the PWM output for HAL 373x devices only 0: 1 kHz 1: 500 Hz 2: 200 Hz 3: 2 kHz (11 bit)
9:8	Output Short Detection	0: Disabled 1: High & low side over current detect. Error Band = High: OUT = VSUP Error Band = Low: OUT = GND 2: High & low side over current detect. Error Band = High: OUT = GND Error Band = Low: OUT = VSUP 3: Low side over current detection OUT = Tristate in error case
7	Error Band	Error band selection for locked devices (Customer Lock bit set). 0: High error band (VSUP) 1: Low error band (GND) The sensor will always go to high error band as long as it is not locked (Customer Lock bit not set).
6	Burn-In Mode	0: Disabled 1: Enabled
5	Functionality Mode	0: Extended 1: Normal (see Section 4.8. on page 23)
4	Communication Mode (POUT)	Communication via output pin 0: Disabled 1: Enabled
3	Overvoltage Detection	Overvoltage detection active Overvoltage detection disabled

Table 3-1: Customer Setup Register

Bit no.	Function	Description
2	Diagnosis Latch	Latching of diagnosis bits 0: No latching 1: Latched till next POR (power-on reset)
1	Diagnosis	O: Diagnosis errors force output to error band (V _{SUP}) 1: Diagnosis errors do not force output to error band (V _{SUP})
0	Customer Lock	Bit must be set to 1 to lock the sensor memory

The Output Short Detection feature is implemented to detect a short circuit between two sensor outputs. The customer can define how the sensor should signalize a detected short circuit (see table above). The time interval in which the sensor is checking for an output short and the detectable short circuit current are defined in Section 4.8. on page 23.

This feature should only be used in case that two sensors are used in one module. In case that the Output Short Detection is not active both sensors will try to drive their output voltage and the resulting voltage will be within the valid signal band.

Note: The Output Short Detection feature is only active after setting the Customer Lock bit and a power-on reset.

3.5. On-board Diagnostic Features

The HAL37xy features two groups of diagnostic functions. The first group contains basic functions that are always active. The second group can be activated by the customer and contains supervision and self-tests related to the signal path and sensor memory.

Diagnostic features that are always active:

- Wire break detection for supply and ground line
- Undervoltage detection
- Thermal supervision of output stage (overcurrent, short circuit, etc.)
- EEPROM self-test at power-on

Diagnostic features that can be activated by customer:

- Continuous EEPROM self-test
- ROM parity check
- Output signal clamping
- A/D converter clipping
- Continuous DSP self-test
- Magnetic range detection
- Overvoltage detection

In case of HAL 3715 and HAL 372x, the sensor indicates a fault immediately by switching the output signal to the selected error band in case that the diagnostic mode is activated by the customer. The customer can select if the output goes to the upper or lower error band by setting bit number 7 in the CUST_SETUP register (Table on page 14). An output short drives the output to VSUP, GND or tristate depending of the customer settings. Further details can be found in Section 4.8. on page 23.

The sensor switches the output to tristate if an over temperature is detected by the thermal supervision. The sensor switches the output to ground in case of a V_{SUP} wire break and to VSUP in case of a GND wire break.

HAL 373x indicates a failure by changing the PWM frequency. The different errors are then coded in different duty-cycles.

Table 3-2: Failure indication for HAL 373x

Failure Mode	Frequency	Duty-Cycle
EEEPROM, ROM and DSP self-test	50%	95%
Magnetic field too low	50%	62.5%
Magnetic field too high	50%	55%
Overvoltage	50%	75%
Undervoltage	No PWM	n.a.
A/D converter clipping	50%	70%

In case of undervoltage, the PWM signal will be constantly 'high' or 'low' depending on the setting of bit number 7 in the CUST_SETUP register. Default setting is 'high' level.

Note: In case of an error, the sensor changes the selected PWM frequency. Example:

During normal operation the PWM frequency is 1 kHz, in case of an error 500 Hz.

3.6. SENT Output

The implementation of the SENT (Single-Edge Nibble Transmission) interface of HAL 373x according to SAE J2716 release 2010-01.

Fig. 3–7 shows the general SENT protocol format. Every transmission starts with a low pulse. The signal is transmitted by the sensor as a series of pulses and data measured as falling to falling edge times.

The SENT telegram consists of a synchronization / calibration period, a status & communication nibble, three data nibbles, and a CRC nibble and a pause period. See Section 4.8. on page 23 for the timing parameters of a telegram.

All timing values in a SENT protocol are referenced to the clock tick time t_{tick} .

After reset the output is recessive high. The transmission starts with a low pulse of the synchronization phase (Fig. 3–7). Every low pulse has the same length specified by the parameter t_{nlow} . The synchronization period has always the same length of clock cycles. The clock variation is included in the parameter t_{sync} . The following status and data nibbles always start with a low pulse with t_{nlow} . The nibble high time of the status t_{stat} , the data $t_{d3,2,1}$ and the CRC t_{crc} depends on the transmitted value. Therefore, the message time of a SENT message depends on the tick time and the value which is transmitted by the message.

In order to synchronize the SENT messages to the measurement sampling rate an additional pause period is added, which is transmitted after the check-sum nibble.

The time to transmit one message is calculated by: $t_{message} = t_{sync} + t_{stat} + t_{d3} + t_{d2} + t_{d1} + t_{crc}$

The checksum nibble is a 4 bit CRC of the data nibbles only. The status & communication nibble is not included in the CRC calculation. The CRC is calculated using polynomial $x^4+x^3+x^2+1$ with seed value of 5. See SAE J2716 for further CRC implementation details.

As recommended by the SAE J2716 an additional zero nibble in addition to the 3 data nibbles for the CRC calculation has been implemented. This is a safety measure against common errors in the last data nibble and the checksum.

In HAL 373x the transmitted data nibbles are generated based on the DAC register value. Special data codes have been implemented for error indication via the SENT interface. The angular or linear position information is coded in the signal range from 2 ... 4087 LSB in the 12 bit range. Table 3–3 gives an overview on the data nibble content.

HAL 373x is not using the status nibble for additional information transmission.

Table 3-3: Data Nibble Content SENT

12-bit value	Definition
4092 to 4095	Reserved
4091	Device Error: Device is failing in one of the self tests (EEPROM, ROM, DSP, Overvoltage)
4090	Signal Path Error: MAG-HIGH or -LOW are exceeded, adder overflow or clipping of channel 1 or 2
4089	Reserved
4088	Clamp-High: Upper signal range violation
2 to 4087	Angular or Position information
1	Clamp-Low: Lower signal range violation
0	During Initialization - Power Up

The SENT protocol starts after the initialization time of the sensor to ensure valid data after power-up.

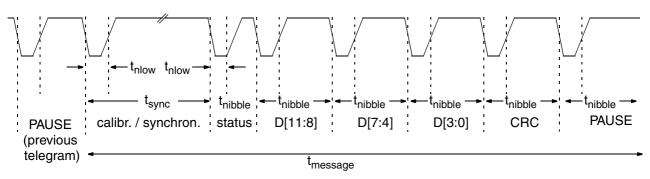


Fig. 3-7: SENT protocol format with 3 data nibbles and pause period

4. Specifications

4.1. Outline Dimensions

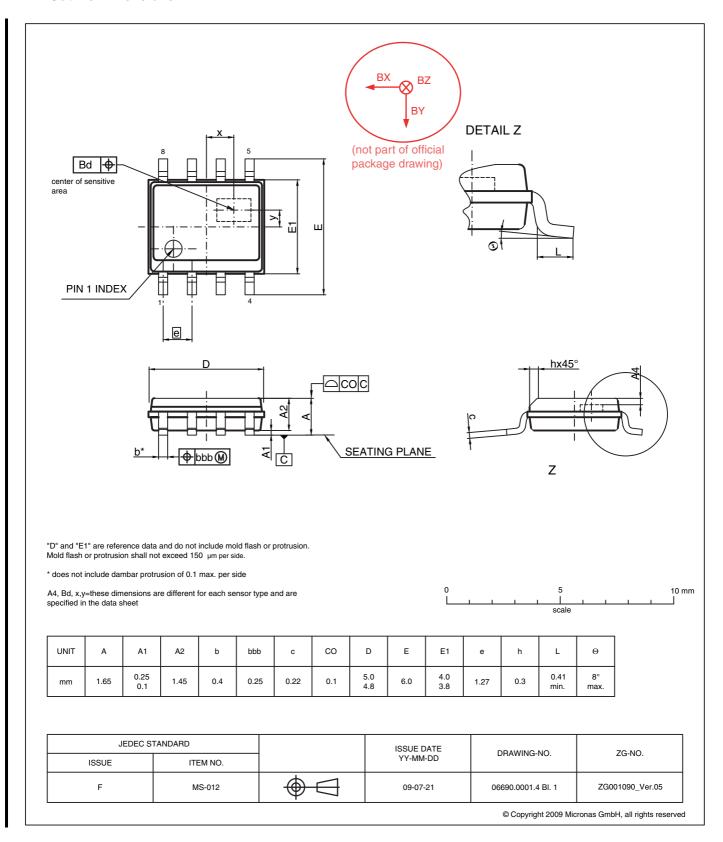


Fig. 4-1:

SOIC8-1: Plastic Small Outline IC package, 8 leads, gullwing bent, 150 mil

Ordering code: DJ

Weight approximately 0.086 g

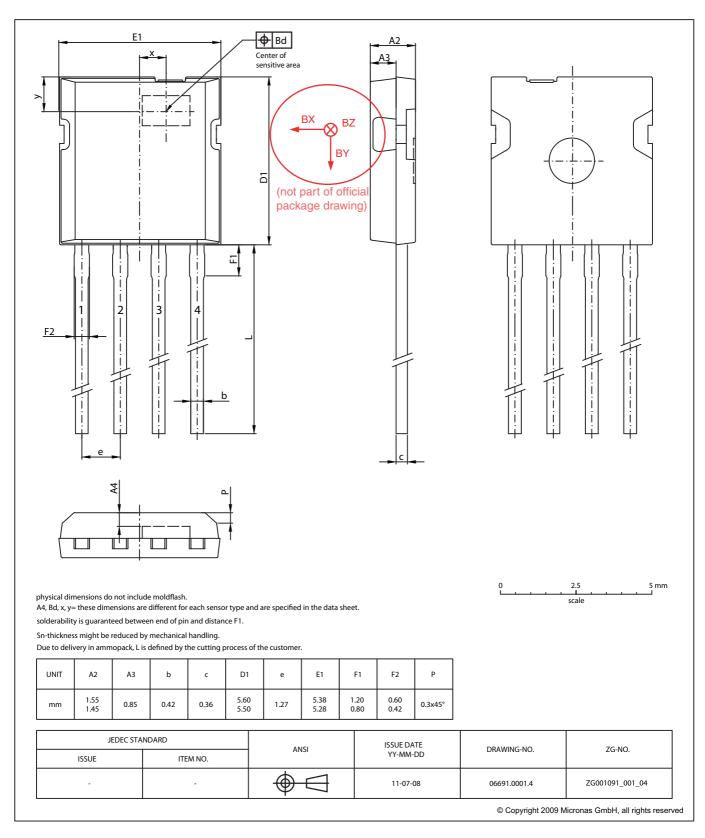


Fig. 4–2: TO92UP: Plastic Transistor Standard UP package, 4 leads Weight approximately 0.105 g

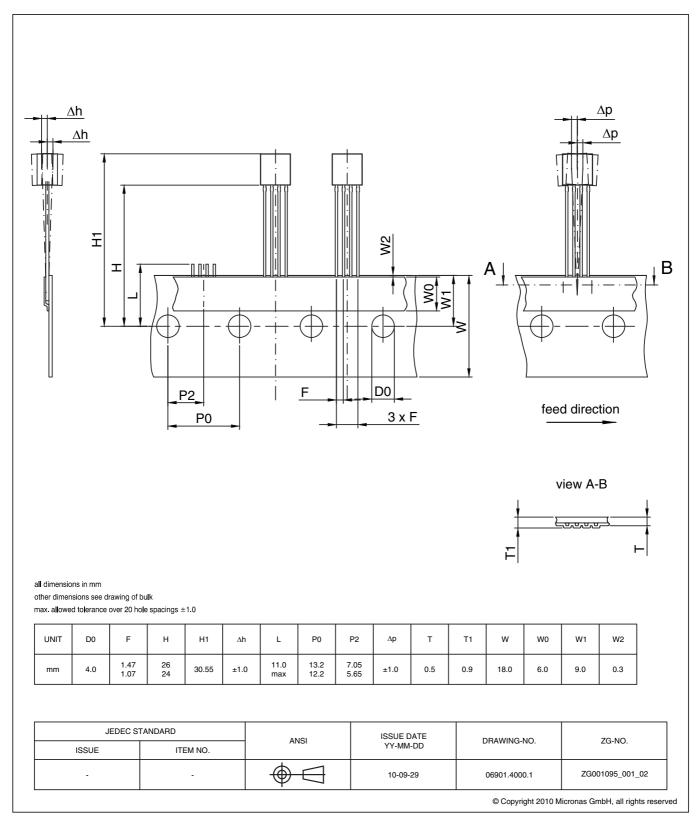


Fig. 4–3: TO92UP: Dimensions ammopack inline, not spread

4.2. Soldering, Welding, Assembly

Information related to solderability, welding, assembly, and second-level packaging is included in the document "Guidelines for the Assembly of Micronas Packages".

It is available on the Micronas website (http://www.micronas.com/en/service-center/downloads) or on the service portal (http://service.micronas.com).

4.3. Sensitive Area

4.3.1. Physical Dimension

 $275 \mu m \times 275 \mu m$

4.3.2. Package Parameters and Position

	SOIC8-1	TO92UP-1
A4	0.38 mm nominal	0.45 mm nominal
Bd	0.3 mm	0.3 mm
х	0 mm nominal (center of package)	0 mm nominal (center of package)
у	0 mm nominal (center of package)	1.90 mm nominal

4.4. Pin Connections and Short Description

Pin No.		Pin Name	Туре	Short Description
TO92UP Package	SOIC8 Package			
1	1	VSUP	SUPPLY	Supply Voltage Pin
2	2	GND	GND	Ground
3	3	TEST	IN	Test
4	4	OUT	I/O	Push-Pull Output and Programming Pin
_	5, 6, 7, 8	NC	GND	connect to GND

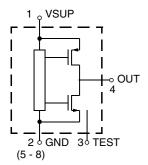


Fig. 4-4: Pin configuration

Note: It is recommended to connect the TEST pin with the GND pin.

4.5. Absolute Maximum Ratings

Stresses beyond those listed in the "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only. Functional operation of the device at these conditions is not implied. Exposure to absolute maximum rating conditions for extended periods will affect device reliability.

This device contains circuitry to protect the inputs and outputs against damage due to high static voltages or electric fields; however, it is advised that normal precautions be taken to avoid application of any voltage higher than absolute maximum-rated voltages to this high-impedance circuit.

All voltages listed are referenced to ground (GND).

Symbol	Parameter	Pin No.	Min.	Max.	Unit	Condition
V _{SUP}	Supply Voltage	VSUP	-18	18	V	t < 1 hr
V _{OUT}	Output Voltage	VSUP	-6	18	V	t < 1 hr
V _{OUT} - V _{SUP}	Excess of Output Voltage over Supply Voltage	OUT, VSUP	-	2	V	
l _{OUT}	Continuous Output Current	OUT	-10	10	mA	
ТЈ	Junction Temperature under Bias		-50	190	°C	1)
B _{max}	Magnetic Field	-	_	unlimited	Т	
V _{ESD}	ESD Protection	VSUP, OUT, TEST, GND, NC	-4	4	kV	2)

¹⁾ For 96 h - Please contact Micronas for other temperature requirements

²⁾ AEC-Q100-002 (100 pF and 1.5 kΩ)

4.6. Storage and Shelf Life

Information related to storage conditions of Micronas sensors is included in the document "Guidelines for the Assembly of Micronas Packages". It gives recommendations linked to moisture sensitivity level and long-term storage.

It is available on the Micronas website (http://www.micronas.com/en/service-center/downloads) or on the service portal (http://service.micronas.com).

4.7. Recommended Operating Conditions

Functional operation of the device beyond those indicated in the "Recommended Operating Conditions/Characteristics" is not implied and may result in unpredictable behavior, reduce reliability and lifetime of the device.

All voltages listed are referenced to ground (GND).

Symbol	Parameter	Pin No.	Min.	Тур.	Max.	Unit	Condition
V _{SUP}	Supply Voltage	VSUP	4.5 5.7	5 6.0	5.5 6.5	V	Normal Operation During Programming
Гоит	Continuous Output Current	OUT	-1.2 -	1 1	1.2 5.5	mA mA	HAL3715 and HAL372x HAL373x
R_L	Load Resistor	OUT	5	10	_	kΩ	HAL3715 and HAL372x pull-up & pull-down resistor
			1	_	_	kΩ	HAL373x pull-up resistor
C _L	Load Capacitance	OUT	0.33	47 -	330 1	nF nF	HAL3715 and HAL372x HAL373x
N _{PRG}	Number of Memory Programming Cycles ¹⁾	ı	ı	ı	100	cycles	0 °C < T _{amb} < 55 °C
B _{AMP}	Recommended Magnetic Field Amplitude	ı	±20	1	±100	mT	
TJ	Junction Temperature ²⁾		-40 -40 -40	-	125 150 170	ÔÔÔÔ	for 8000 hrs for 2000 hrs for 1000 hrs Time values are not additive.

¹⁾ The EEPROM is organized in three banks. Each bank contains up to 32 addresses. It is not allowed to program only one single address within one of the three banks. In case of programming one single address the complete bank has to be programmed.

Note: It is also possible to operate the sensor with magnetic fields down to ± 5 mT. For magnetic fields below ± 20 mT the sensor performance will be reduced.

²⁾ Depends on the temperature profile of the application. Please contact Micronas for life time calculations.

4.8. Characteristics

at T_J = -40 °C to +170 °C, V_{SUP} = 4.5 V to 5.5 V, GND = 0 V, after programming and locking of the sensor, at Recommended Operation Conditions if not otherwise specified in the column "Conditions". Typical Characteristics for T_J = 25 °C and V_{SUP} = 5 V.

$t_{\text{AVS}} \qquad \text{Wake-up time}^{2} \qquad \text{OUT} \qquad - \qquad 12 \qquad - \qquad \text{bit} \qquad \text{for HAL 373x (dependent)} \\ t_{\text{AVS}} \qquad \text{Wake-up time}^{2} \qquad \text{OUT} \qquad - \qquad - \qquad 1.7 \qquad \text{ms} \qquad C_L = 10 \text{ nF (see Figpage 26)} \\ \text{Overvoltage and Undervoltage Detection} \\ \text{VSUP,UV} \qquad \text{Undervoltage Detection Level robust mode} \qquad \text{VSUP} \qquad 3.3 \qquad 3.9 \qquad 4.3 \qquad \text{V} \qquad \text{NormalFunctionality Mode: NormalFunctionality Extended CUST_SI bit 5} \\ \text{VSUP,UVhyst} \qquad \text{Undervoltage Detection Level rysteresis}^{2} \qquad \text{VSUP} \qquad - \qquad 200 \qquad - \qquad \text{mV} \\ \text{VSUP,OV} \qquad \text{Overvoltage Detection Level rysteresis}^{2} \qquad \text{VSUP} \qquad - \qquad 2200 \qquad - \qquad \text{mV} \\ \text{VSUP,OVhyst} \qquad \text{Overvoltage Detection Level rhysteresis}^{2} \qquad \text{VSUP} \qquad - \qquad 225 \qquad - \qquad \text{mV} \\ \text{NormalFunctionality Extended CUST_SI bit 5} \\ \text{VSUP,OVhyst} \qquad \text{Overvoltage Detection Level rhysteresis}^{2} \qquad \text{VSUP} \qquad - \qquad 225 \qquad - \qquad \text{mV} \\ \text{Output Voltage in Case of Error Detection} \\ \text{VSUP,DVAG} \qquad \text{Supply Voltage required to get defined Output Voltage Level}^{2} \qquad \text{VSUP} \qquad - \qquad 2.3 \qquad - \qquad \text{V} \qquad \text{Output behavior seed to get defined Output Voltage Level}^{2} \\ \text{VError,Low} \qquad \text{Output Voltage Range of Lower Error Band}^{2} \qquad \text{OUT} \qquad 0 \qquad - \qquad 4 \qquad \text{NVSUP} \qquad \text{VSUP} > \text{VSUP} > \text{VSUP} \text{DAG Analog Output} \\ \text{S kΩ \leq R_L \leq = 200 ks} \\ \text{Output Short Detection Parameter} \\ \text{Voc} \qquad \text{Over Current Detection} \qquad \text{OUT} \qquad - \qquad 256 \qquad - \qquad \text{ms} \\ \text{Valimenut} \qquad \text{Time Period without Over} \qquad \text{OUT} \qquad - \qquad 256 \qquad - \qquad \text{ms} \\ \text{Instance} \qquad \text{Time Period without Over} \qquad \text{OUT} \qquad - \qquad 256 \qquad - \qquad \text{ms} \\ \text{Instance} \qquad \text{Time Period without Over} \qquad \text{OUT} \qquad - \qquad 256 \qquad - \qquad \text{ms} \\ \text{Instance} \qquad Insta$	Symbol	Parameter	Pin No.	L	imit Valu	ues	Unit	Test Conditions
over Temperature Range Resolution $^{1)}$ OUT $^{-}$ 12 $^{-}$ $^{-}$ 12 $^{-}$ bit for HAL3715/HAL3 ratiometric to VSUP for HAL373x (deper Period) Overvoltage and Undervoltage Detection VSUPUV Undervoltage Detection Level robust mode VSUP $^{-}$				Min.	Тур.	Max.		
$t_{\text{LMS}} \qquad \text{Wake-up time}^{2)} \qquad \text{OUT} \qquad - \qquad 12 \qquad - \qquad \text{bit} \qquad \begin{array}{c} \text{ratiometric to VSUP} \\ \text{for HAL373x (dependent)} \\ \text{Value} \qquad \text{Value} \qquad \text{Value} \qquad \text{Value} \qquad - \qquad 1.7 \qquad \text{ms} \qquad \text{C}_L = 10 \text{ nF (see Figpage 26)} \\ \text{Overvoltage and Undervoltage Detection} \\ \text{Value} \qquad V$	SUP		VSUP	_	8	13	mA	
$t_{\text{LMys}} \qquad \text{Wake-up time}^{2)} \qquad \text{OUT} \qquad - \qquad 12 \qquad - \qquad \text{bit} \qquad \text{for HAL373x (deperence)} \\ \text{Vour-voltage} \qquad \text{OUT} \qquad - \qquad - \qquad 1.7 \qquad \text{ms} \qquad \text{C}_L = 10 \text{ nF (see Figpage 26)} \\ \text{Overvoltage and Undervoltage Detection} \\ \text{VSUPUV} \qquad \text{Undervoltage Detection Level robust mode} \qquad \text{VSUP} \qquad 3.3 \qquad 3.9 \qquad 4.3 \qquad \text{V} \qquad \text{Functionality Mode:} \\ \text{NormalFunctionality} \\ \text{Extended CUST_Sibit 5} \\ \text{VSUP,UVhyst} \qquad \text{Undervoltage Detection Level Hysteresis} \qquad \text{VSUP} \qquad - \qquad 200 \qquad - \qquad \text{mV} \\ \text{WSUP,OV} \qquad \text{Overvoltage Detection Level VSUP} \qquad - \qquad 200 \qquad - \qquad \text{mV} \\ \text{VSUP,OVhyst} \qquad \text{Overvoltage Detection Level Hysteresis} \qquad \text{VSUP} \qquad - \qquad 225 \qquad - \qquad \text{mV} \\ \text{SUP,OVhyst} \qquad \text{Overvoltage Detection Level Hysteresis} \qquad \text{VSUP} \qquad - \qquad 225 \qquad - \qquad \text{mV} \\ \text{Output Voltage in Case of Error Detection} \\ \text{VSUP,DIAG} \qquad \text{Supply Voltage required to get defined Output Voltage Level} \qquad \text{VSUP} \qquad - \qquad 2.3 \qquad - \qquad \text{V} \qquad \text{Output behavior seed of Error Band} \\ \text{V}_{\text{Error,Low}} \qquad \text{Output Voltage Range of Lower Error Band} \qquad \text{OUT} \qquad 0 \qquad - \qquad 4 \qquad \text{``VSUP} \qquad \text{V}_{\text{SUP}} > V$		Resolution 1)	OUT	-	12	-	bit	for HAL3715/HAL372x
Overvoltage and Undervoltage Detection V _{SUP,UV} Undervoltage Detection Level robust mode VSUP 3.3 and 3.9 and 4.1 and 3.1 and 3.7 and 4.1 by Functionality Mode: NormalFunctionality Extended CUST_St bit 5 V _{SUP,UV} hyst Undervoltage Detection Level Hysteresis ² VSUP - 200 - mV mV V _{SUP,OV} Overvoltage Detection Level Hysteresis ² VSUP - 256 and 5.9 and 5.6 bit 5 6.2 and 5.9 and 5.9 and 5.0 and 5.0 bit 5 V Functionality Mode: NormalFunctionality Extended CUST_St bit 5 V _{SUP,OV} hyst Overvoltage Detection Level Hysteresis ² VSUP - 225 - mV mV Functionality Mode: NormalFunctionality Extended CUST_St bit 5 Output Voltage in Case of Error Detection VSUP - 225 - mV To V Output Detection Cust bit 5 V _{SUP,DIAG} and Cust of Error Detection VSUP - 2.3 - V V Output behavior set of St Cust bit 5 V _{Error,Low} and Cust of Error Band ² OUT - 2.3 - V V Output Detection Cust behavior set of St Cust bit 5 Output Voltage Range of Upper Error Band ² OUT - 2.0 - V Analog Output 5 kΩ ≤ R _L <= 200 ks Output Short Detection Parameter OUT - 128 - ms Image: St Cust bit 5 bit 5 V _{Error,High} and Cust of Error Detection Parameter OUT - 256 - ms Ms				-	12	-	bit	for HAL373x (depends on PWM
$V_{SUP,UV} \begin{tabular}{ l l l l l l l l l l l l l l l l l l l$	[‡] ΔVs	Wake-up time ²⁾	OUT	-	-	1.7	ms	C _L = 10 nF (see Fig. 4–5 on page 26)
robust mode	Overvoltage	and Undervoltage Detection			•	•	•	
$V_{SUP,OV} \text{Overvoltage Detection Level} VSUP \begin{array}{c} 5.6 \\ 8.5 \\ \end{array} \begin{array}{c} 6.2 \\ 9.5 \\ \end{array} \begin{array}{c} 6.9 \\ 10.4 \\ \end{array} \begin{array}{c} V \\ \text{NormalFunctionality Mode:} \\ \text{NormalFunctionality Extended CUST_SI} \\ \text{bit 5} \\ \end{array}$ $V_{SUP,OVhyst} \begin{array}{c} \text{Overvoltage Detection Level} \\ \text{Hysteresis}^{(2)} \end{array} VSUP - \begin{array}{c} 225 \\ \end{array} - \text{mV} \\ \end{array}$ $\begin{array}{c} \text{Output Voltage in Case of Error Detection} \\ V_{SUP,DIAG} \begin{array}{c} \text{Supply Voltage required to} \\ \text{get defined Output Voltage} \\ \text{Level}^{(2)} \end{array} VSUP - \begin{array}{c} 2.3 \\ \end{array} - \begin{array}{c} V \\ \text{Output behavior see} \\ \text{Analog Output} \\ \text{Sk}\Omega \leq R_{L} <= 200 \text{ ks} \\ \end{array}$ $\begin{array}{c} \text{V}_{Error,Low} \text{Output Voltage Range of} \\ \text{Upper Error Band}^{(2)} \end{array} \text{OUT} 96 - \begin{array}{c} 100 \\ \text{SW} \\ \text{SUP} \\ \text{SW} \leq R_{L} <= 200 \text{ ks} \\ \end{array}$ $\begin{array}{c} \text{Output Short Detection Parameter} \\ \text{Timeout} \text{Time Period without Over} \qquad \text{OUT} - \begin{array}{c} 256 \\ \text{COD} \end{array} \text{ms} $	V _{SUP,UV}		VSUP					Functionality Mode: NormalFunctionality Mode: Extended CUST_SETUP register bit 5
$ \begin{array}{ c c c c c c c c c c c c c c c c c c c$	V _{SUP,UVhyst}	Undervoltage Detection Level Hysteresis ²⁾	VSUP	-	200	-	mV	
Output Voltage in Case of Error Detection $V_{SUP,DIAG}$ Supply Voltage required to get defined Output Voltage Level ^[2] VSUP - 2.3 - V Output behavior set of the parameter $V_{Error,Low}$ Output Voltage Range of Lower Error Band ^[2] OUT 0 - 4 %VSUP VSUP > VSUP,DIAG Analog Output 5 k Ω ≤ RL <= 200 kg	V _{SUP,OV}	Overvoltage Detection Level	VSUP					Functionality Mode: NormalFunctionality Mode: Extended CUST_SETUP register bit 5
$\begin{array}{c ccccccccccccccccccccccccccccccccccc$	V _{SUP,OVhyst}	Overvoltage Detection Level Hysteresis ²⁾	VSUP	_	225	-	mV	
$\begin{array}{c ccccccccccccccccccccccccccccccccccc$	Output Volta	ge in Case of Error Detection			•	•	•	
$V_{Error,High} \begin{array}{c ccccccccccccccccccccccccccccccccccc$	V _{SUP,DIAG}	Supply Voltage required to get defined Output Voltage Level ²⁾	VSUP	-	2.3	-	V	Output behavior see Fig. 4–6
	V _{Error,Low}	Output Voltage Range of Lower Error Band ²⁾	OUT	0	-	4	%V _{SUP}	$\begin{array}{l} V_{SUP} > V_{SUP,DIAG} \\ \text{Analog Output} \\ 5 \text{ k}\Omega \leq R_L <= 200 \text{ k}\Omega \end{array}$
t_{OCD} Over Current Detection OUT - 128 - μs $t_{TimeOut}$ Time Period without Over OUT - 256 - μs	V _{Error,High}		OUT	96	-	100	%V _{SUP}	
Time ²⁾ t _{Timeout} Time Period without Over OUT – 256 – ms	Output Shor	t Detection Parameter						
	OCD		OUT	-	128	_	μs	
Current Detection ⁻⁷	Timeout	Time Period without Over Current Detection ²⁾	OUT	_	256	_	ms	
I _{OVC} Detectable Output Short OUT – 10 – mA	ovc	Detectable Output Short Current ²⁾	OUT	-	10	-	mA	

Guaranteed by Design
 Characterized on small sample size, not tested.

Symbol	Parameter	Pin No.	L	imit Val	ues	Unit	Test Conditions
			Min.	Тур.	Max.		
HAL3715 a	and HAL372x (Analog Output)						
$t_{r(O)}$	Response Time of Output ²⁾	OUT	_	0.5	0.6	ms	$C_L = 10$ nF, time from ideal step to 90% of final output
							For 8 kHz sample frequency
DNL	Differential Non-Linearity of D/A converter	OUT	-3	0	3	LSB	
E _R	Ratiometric Error of Output over temperature	OUT	-0.2	0	0.2	%	Max of [V _{OUT5} – V _{OUT4.5} and V _{OUT5.5} – V _{OUT5}] at V _{OUT} = 10%
	(Error in V _{OUT} /V _{SUP})						and 90% V _{SUP}
INL	Non-Linearity of D/A converter	OUT	-0.1	0	0.1	%	% of supply voltage
ΔV _{OFFSET}	D/A converter offset drift over temperature range related to 25 °C ²⁾	OUT	-0.2	0	0.2	%V _{SUP}	
V _{OUTH}	Output High Voltage 3)	OUT	93	_	_	%V _{SUP}	R_L Pull-up/-down = 5 k Ω
V _{OUTL}	Output Low Voltage 3)	OUT	_	_	7	%V _{SUP}	R_L Pull-up/-down = 5 k Ω
ΔV _{OUTCL}	Accuracy of Output Voltage at Clamping Low Voltage over Temperature Range ²⁾	OUT	-30	0	30	mV	R_L Pull-up/-down = 5 kΩ V_{SUP} = 5V
ΔV _{OUTCH}	Accuracy of Output Voltage at Clamping High Voltage over Temperature Range ²⁾	OUT	-30	0	30	mV	
OUT _{Noise}	Output Noise RMS ²⁾	OUT	-	3.5	-	mV	Min. magnetic amplitude = ±20 mT
			-	1.0	_	mV	Min. magnetic amplitude = $\pm 70 \text{ mT}$ with external capacitor at the output $f_C = 22 \text{ kHz}$
R _{OUT}	Output Resistance over Recommended Operating Range	OUT	-	1	10	Ω	$V_{OUTLmax} \le V_{OUT} \le V_{OUTHmin}$
Open-Circu	uit Detection						
V _{OUT}	Output voltage at open V _{SUP} line	OUT	0	0	0.15	V	$V_{SUP} = 5 V$ $R_L^{4)} = 10 kΩ to 200 kΩ$
			0	0	0.2	V	$V_{SUP} = 5 V$ $5 k\Omega \le R_L^{4} < 10 k\Omega$
V _{OUT}	Output voltage at open GND line	OUT	4.85	4.9	5.0	V	$V_{SUP} = 5 V$ $R_L^{4)} = 10 kΩ$ to 200 kΩ
			4.8	4.9	5.0	V	$V_{SUP} = 5 V$ $5 kΩ ≤ R_L^{4} < 10 kΩ$

Characterized on small sample size, not tested.
 Signal band area with full accuracy is located between V_{OUTL} and V_{OUTH}. The sensors accuracy is reduced below V_{OUTL} and above V_{OUTH}
 RL can be pull-up or pull-down resistor

Symbol	Parameter	Pin No.	L	imit Valu	ies	Unit	Test Conditions	
			Min.	Тур.	Max.			
HAL373x (D	rigital Output)							
V _{OUTH}	Output High Voltage	OUT	-	4.9	-	V	V _{SUP} = 5 V, I _{OUT} = 5 mA	
V _{OUTL}	Output Low Voltage	OUT	_	0.1	-	V	$V_{SUP} = 5 \text{ V}, I_{OUT} = -5 \text{ mA}$	
t _{rise}	Rise Time of Digital Output	OUT	-	0.4	-	μs	R _L Pull-up= 1 kΩ, CL = 1 nF	
t _{fall}	Fall Time of Digital Output	OUT	-	0.5	-	μs	R_L Pull-up= 1 kΩ, CL = 1 nF	
ROUT_DIG	On Resistance of Digital Pull- Up Driver	OUT	_	100	200	Ω	Includes 25 Ω series pull-up resistor and 50 Ω pull-down	
PWM Outpu	t							
t _{r(O)}	Response Time of Output ²⁾	OUT	_	_	0.6	ms	For PWM frequencies slower that 2 kHz the response time is dominated by the selected PWI frequency.	
OUT _{Noise}	Output Noise RMS 2)	OUT	_	0.07	_	%	Min. magnetic amplitude =	
			-	0.02	_	%	±20 mT Min. magnetic amplitude = ±70 mT with external capacitor C _L =1nF on the output	
							Related to 100% DC	
f _{PWM}	PWM Frequency	OUT	1800 900 450 180	2000 1000 500 200	2200 1100 550 220	Hz	Customer programmable	
J _{PWM}	RMS PWM Jitter ²⁾	OUT	_	1	2	LSB ₁₂	f _{PWM} = 1 kHz	
SENT Outpu	ut							
t _{startup}	Start-up Time	OUT	_	1.3	1.7	ms		
t _{tick}	Clock Tick Time	OUT	_	2.75	_	μs		
t _{nlow}	Nibble Low Time	OUT	_	5	_	t _{tick}		
t _{sync}	Calibration / Synchronization Period	OUT	_	56	-	t _{tick}		
t _{nibble}	Status & Communication Nibble, Data Nibbles and CRC Nibble Period	OUT	12	_	27	t _{tick}	t _{nibble} = 12 + [status data CRC]	
t _{message}	Message Time	OUT	116	-	176	t _{tick}		
t _{pause}	Pause Period Time	OUT	12	_	70	t _{tick}		

Symbol	Parameter	Pin No.	L	Limit Values		Unit	Test Conditions	
			Min.	Тур.	Max.			
SOIC8 Pa	ckage			•	.	•		
	Thermal Resistance						(Self-heating calculation see	
R _{thja}	Junction to Air	-	_	_	115	K/W	Section 5.1. on page 30) Measured with a 1s1p board	
R _{thic}	Junction to Case	_	_	_	110	K/W	Measured with a 2s2p board	
' 'tnjc	dunction to case				33	K/W	Measured with a 1s1p board	
TO92UP F	Package							
	Thermal Resistance						(Self-heating calculation see	
R _{thja}	Junction to Air	_	-	-	100	12/14/	Section 5.1. on page 30)	
		_	_	_	198	K/W	Measured with a 1s0p board	
R _{thic}	Junction to Case	_	_	_	146	K/W	Measured with a 1s1p board	
unjo		_	_	_	53	K/W	Measured with a 1s0p board	
					38	K/W	Measured with a 1s1p board	

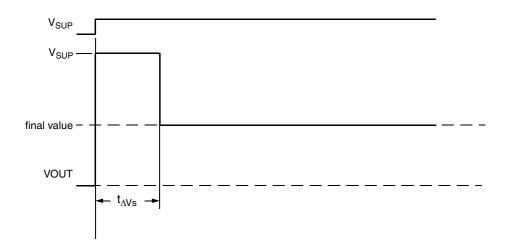


Fig. 4-5: POR timing

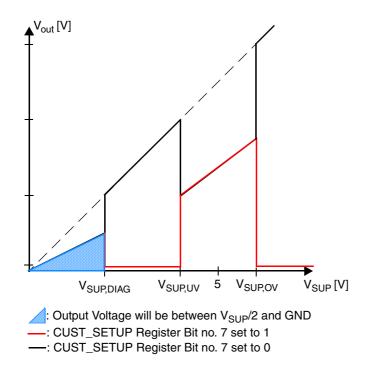


Fig. 4–6: Behavior of HAL3715 and HAL372x for different $V_{\mbox{SUP}}$

4.9. Magnetic Characteristics

at $T_J = -40$ °C to +170 °C, $V_{SUP} = 4.5$ V to 5.5 V, GND = 0 V, after programming and locking of the sensor, at Recommended Operation Conditions if not otherwise specified in the column "Conditions". Typical Characteristics for $T_J = 25$ °C and $V_{SUP} = 5$ V.

Symbol	Parameter	Pin No.	Min.	Тур.	Max.	Unit	Test Conditions
⊕ _{RANGE}	Detectable angle range	OUT	0	_	360	0	
Θ_{res}	Angle resolution	OUT	_	_	0.09	0	(360°/4096)
E_{\Thetalinxy}	XY angle linearity error (on output of CORDIC filter)	OUT	-0.5	-	0.5	0	Min. $B_{AMP} = \pm 30 \text{ mT},$ $T_J = 25 {}^{\circ}\text{C}^{1)} {}^{2)}$
E_{\Thetalinxy}	X/Y angle linearity error over	OUT	-1.2	-	1.2	0	Min. B _{AMP} =±30 mT ^{1) 2)}
	temperature (on output of CORDIC filter)		-1.7	-	1.7		Min. B _{AMP} =±20 mT ^{1) 2)}
ASMm _{X/Y_Z}	Absolute sensitivity mismatch on raw signals between X/Y and Z channel	OUT	-3 -10	-	3 +10	% %	for SOIC8 package for TO92UP package T _J =25 °C ¹⁾
Sense _{XYZ}	Sensitivity of X/Y and Z Hall Plate	OUT	118	128	138	LSB/ mT	T _J =25 °C ¹⁾
∆Sense _{XY}	Sensitivity Drift of Vertical Hall Plates over temperature	OUT	-1.5	-	1.5	%	over full temperature range related to 25 °C ¹⁾
∆Sense _Z	Sensitivity Drift of Horizontal Hall Plates over temperature	OUT	-1.5	-	1.5	%	over full temperature range related to 25 °C ¹⁾
$SMm_{X/Y_{Z}Z}$	Thermal sensitivity mismatch drift of calibrated signals between X/Y and Z channel	OUT	-2.5	_	2.5	%	over full temperature range related to 25 °C ¹⁾
SMm _{XY}	Thermal sensitivity mismatch drift of calibrated signals between X and Y channel	OUT	-2	_	2	%	over full temperature range related to 25 °C ¹⁾
Offset _{XY}	Offset of calibrated signals of X or Y channel	OUT	-20	-	20	LSB ₁₅	T _J =25 °C ¹⁾ Can be compensated in customer application
Offset _Z	Offset of calibrated signal of Z channel	OUT	-12	-	12	LSB ₁₅	T _J =25 °C ¹⁾ Can be compensated in customer application
$\Delta Offset_{XY}$	Offset drift of calibrated signals of X or Y channel	OUT	-70	-	70	LSB ₁₅	over full temperature range related to 25 °C ¹⁾
$\Delta Offset_Z$	Offset drift of calibrated signals of Z channel	OUT	-10	ı	10	LSB ₁₅	over full temperature range related to 25 °C ¹⁾
∆SMm _{XYZlife}	Relative sensitivity mismatch drift of calibrated signals between X or Y channel and Z channel over life time	OUT	_	1.0	_	%	after 1000h HTOL ¹⁾
$\Delta Offset_{XYlife}$	Offset drift of calibrated signals of X or Y channel	OUT	_	30	_	LSB ₁₅	after 1000h HTOL ¹⁾
∆Offset _{Zlife}	Offset drift of calibrated signal of Z channel	OUT	-	5	_	LSB ₁₅	after 1000h HTOL ¹⁾

¹⁾ Characterized on sample base, 3-sigma values, not tested for each device ²⁾ Calculated angular error based on characterization and not on single error summation

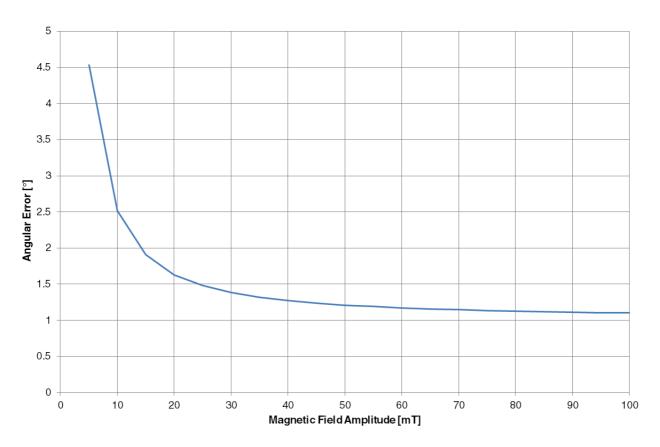


Fig. 4–7: Angular error versus magnetic field amplitude over full temperature range for devices using X and Y magnetic field component (for digital output)

5. Application Notes

5.1. Ambient Temperature

Due to the internal power dissipation, the temperature on the silicon chip (junction temperature T_J) is higher than the temperature outside the package (ambient temperature T_A).

$$T_{,J} = T_A + \Delta T$$

At static conditions and continuous operation, the following equation applies:

$$\Delta T = I_{SUP} * V_{SUP} * R_{thiX}$$

The X represents junction to air, case or solder point.

For worst case calculation, use the max. parameters for I_{SUP} and R_{thjX} , and the max. value for V_{SUP} from the application.

Following example shows the result for junction to air conditions for SOIC8 package.

 V_{SUP} = 5.5 V, R_{thja} = 142 K/W and I_{SUP} = 15 mA the temperature difference ΔT = 11.72 K.

The junction temperature T_J is specified. The maximum ambient temperature T_{Amax} can be calculated as:

$$T_{Amax} = T_{Jmax} - \Delta T$$

5.2. EMC and ESD

Please contact Micronas for detailed information on EMC and ESD results.

5.3. Application Circuit for HAL3715 and HAL372x

For EMC protection, it is recommended to connect one ceramic 47 nF capacitor each between ground and the supply voltage, respectively the output voltage pin.

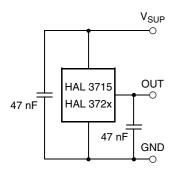


Fig. 5–1: Recommended application circuit for HAL3715 and HAL372x

Note: It is recommended to connect the TEST pin to with the GND pin.

■ 5.4. Application Circuit for HAL373x

PWM Output

In case of PWM output mode, it is recommended to connect one ceramic 47 nF capacitor between ground and the supply voltage and one ceramic 1 nF capacitor between the output pin and ground for EMC protection.

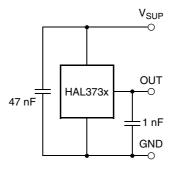


Fig. 5–2: Recommended application circuit for HAL373x in PWM mode

SENT Output

In case of SENT output mode, it is recommended to connect one ceramic 47 nF capacitor between ground and the supply voltage and a filter structure at the output pin for EMC protection as well for having a SENT standard compliant output slew rate.

Following two setups have been tested:

- C01 = 180 pF, C02 = 2.2 nF, R01 = 120 Ω
- C01 = 180 pF, C02 = 3.3 nF, R01 = 180 Ω

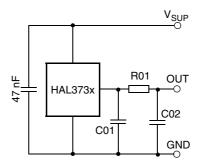


Fig. 5–3: Recommended application circuit for HAL373x

Note: It is recommended to connect the TEST pin with the GND pin.

5.5. Measurement of a PWM Output Signal of HAL373x

In case of the PWM output, the magnetic field information is coded in the duty cycle of the PWM signal. The duty cycle is defined as the ratio between the high time "s" and the period "d" of the PWM signal (see Fig. 5–4).

Note: The PWM signal is updated with the rising edge. Hence, for signal evaluation, the trigger-level must be the rising edge of the PWM signal.

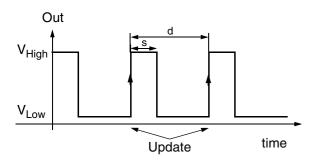
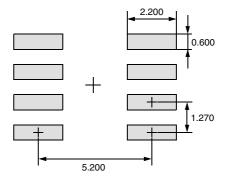


Fig. 5-4: Definition of PWM signal

5.6. Recommended Pad Size SOIC8 Package



Dimensions in mm

6. Programming of the Sensor

HAL 37xy features two different customer modes. In **Application Mode** the sensors provide a ratiometric analog output voltage or a digital output signal (PWM or SENT). In **Programming Mode** it is possible to change the register settings of the sensor.

After power-up the sensor is always operating in the **Application Mode**. It is switched to the **Programming Mode** by a pulse at the sensor output pin.

6.1. Programming Interface

In Programming Mode HAL 37xy is addressed by modulating a serial telegram on the sensors output pin. Both sensors answer with a modulation of the output voltage.

A logical "0" is coded as no level change within the bit time. A logical "1" is coded as a level change of typically 50% of the bit time. After each bit, a level change occurs (see Fig. 6–1).

The serial telegram is used to transmit the EEPROM content, error codes and digital values of the angle information from and to the sensor.

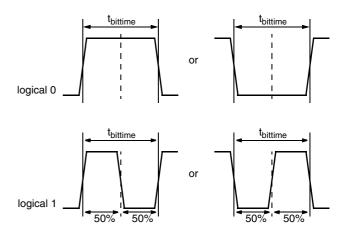


Fig. 6-1: Definition of logical 0 and 1 bit

A description of the communication protocol and the programming of the sensor is available in a separate document (Application Note Programming HAL 37xy).

Table 6–1: Telegram parameters (All voltages are referenced to GND.)

Symbol	Parameter Pin No. Limit Values				Unit	Test Conditions	
			Min.	Тур.	Max.		
V _{OUTL}	Voltage for Output Low Level during Programming through Sensor Output Pin	OUT	0	-	0.2*V _{SUP}	V V	for V _{SUP} = 5 V
V _{OUTH}	Voltage for Output High Level during Programming through Sensor Output Pin	OUT	0.8*V _{SUP}	_	V _{SUP} 5.0	V V	for V _{SUP} = 5 V
V _{SUPProgram}	V _{SUP} Voltage for EEPROM & NVRAM programming (during Programming)	VSUP	5.7	6.0	6.5	V	Supply voltage for bidirectional communication via output pin as well as for 3-wire communication via supply voltage modulation
t _{bittime}	Protocol Bit Time	OUT	900 225	1000 250	1100 275	μs μs	Cust. programmable, $T_J = 25^{\circ}C$ Bit 13 of Customer Setup = 0 Bit 13 of Customer Setup = 1
	Slew rate	OUT	-	2	_	V/µs	

6.2. Programming Environment and Tools

For the programming of HAL 37xy during product development a programming tool including hardware and software is available on request. It is recommended to use the Micronas tool kit (HAL-APB V1.x USB kit and Lab View Programming Environment) in order to facilitate the product development. The details of programming sequences are also available on request.

Note: For production, HAL-APB V1.5 or higher must be used.

6.3. Programming Information

For production and qualification tests, it is mandatory to set the LOCK bit to one and the POUT bit to zero after final adjustment and programming of HAL 37xy.

Before locking the device, it is recommended to read back all register values to ensure that the intended data is correctly stored in the sensor's memory. Alternatively, it is also possible to cross-check the sensor output signal with the intended output behavior.

The success of the LOCK process shall be checked by reading the status of the LOCK bit after locking.

It is also mandatory to check the acknowledge (first and second) of the sensor after each write and store sequence to verify if the programming of the sensor was successful. To enable debugging of the production line, it is recommended to read back the PROG_DIAGNOSIS register in case of a missing second acknowledge. Please check HAL 37xy Programming Guide for further details.

Electrostatic Discharges (ESD) may disturb the programming pulses. Please take precautions against ESD.

Note: Please check also the "HAL 37xy Programming Guide" and relevant documentation for the HAL-APB and the USB-Kit. It contains additional information and instructions about the programming of the devices.

7. Data Sheet History

- Advance Information: "HAL 372x, HAL 373x" Robust Programmable 2D Position Sensor Family with Arbitrary Output Function", Oct. 10, 2013, Al000171_001EN. First release of the advance information.
- Advance Information: "HAL 3715, HAL 372x, HAL 373x Robust Programmable 2D Position Sensor Family with Arbitrary Output Function", June 26, 2014, Al000171_002EN. Second release of the advance information. Major changes:
 - HAL 3715 added to the document
 - Update of customer NVRAM table
 - Adaptation of parameter Y for SOIC-8 package
 - Adaptation of parameter L for TO92-UP package drawing
 - Recommended application circuit for SENT output mode added
 - Update of SENT interface timing
- Preliminary Data Sheet: "HAL 3715, HAL 372x, HAL 373x Robust Programmable 2D Position Sensor Family with Arbitrary Output Function", Feb. 2, 2015, PDI000217_001E. First release of the preliminary data sheet. Major changes:
 - SOIC8 package drawing updated
 - Magnetic characteristics table completed
 - Electrical characteristics table completed
- Preliminary Data Sheet: "HAL 3715, HAL 372x, HAL 373x Robust Programmable 2D Position Sensor Family with Arbitrary Output Function", Aug 7, 2015, PDI000217_002E. Second release of the preliminary data sheet. Major changes:
 - Update of signal path diagram
 - Recommendation added to connect TEST pin with GND pin
 - Typing error in electrical characteristics table for parameter f_{PWM} corrected
 - Max. load capacitance for analog output reduced to 330 nF
 - Product shelf life recommendations modified

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